Integrated entangling quantum logic gate in a scalable surface-electrode ion trap G. Zarantonello^{1,2}, J. Morgner^{1,2}, H. Hahn^{1,2}, A. Bautista-Salvador^{1,2}, M. Schulte¹, K. Hammerer¹ and Christian Ospelkaus^{1,2} ¹Leibniz Universität Hannover, Welfengarten 1, 30167 Hannover, Germany ²PTB, Bundesallee 100, 38116 Braunschweig, Germany



Microwave near-field approach

Classical Mølmer-Sørensen



Goal

• High-fidelity universal gate set by using microwave fields only

Requirements

• Drive carrier and sideband transitions

Advantages

- No spontaneous emission
- Less hardware required
- Potentially better scalability



Experimental setup





coaxial resonator

1 trap

DN16 feedthrough







• Off-resonant carr. exc. : <0.1% • Microwave pulse shape : <0.1%





5 pin sub-d connector

Ion trap designs

RF resonator



Multilayer design features[4,5]

- Substrate: Si/SiN
- Ion-electrode distance: 35 μm
- 10 DC electrodes
- 2 carrier electrodes

- Single layer design features
- Substrate: AIN
- Ion-electrode distance: 70 μm
- 10 DC electrodes
- 2 carrier electrodes

Motivation

Amplitude modulation open the possibility to change the classical circular trajectory in phase space

- Specific trajectories can be more resistant against residual spin-motion entanglement
- Provides insensitivity against motional mode fluctuations
- Dissipates less energy in the trap microstructures



Gate scheme comparison

- To demonstrate resilience we artificially inject noise in the pseudopotential which affects the radial modes • sin² modulation of 17th order vs 7 loop square pulse • square chosen because they dissipate the same energy
 - All measurements are SPAM corrected
 - Theoretical comparison of different schemes shows improvement of about two orders of magnitude

AM gate with 17th order [9]: F=99.7(1)%



 $\phi_{a}[^{\circ}$

150

 Figure d 	of Merit:	> 0.3
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- RF electrode length: 1.6 mm
- Carrier coupling: -28 dB

• Figure of Merit: 0.005 • RF electrode length: 1.45 mm • Carrier coupling: -19 dB



References

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[5] H. Hahn, et al., APB 125 (8), 154 (2019) [6] D. A. Hite *et al.*, PRL 109, 103001 (2012) [7] D.J. Wineland *et al.*, JRNIST 103, 259-328 (1998) [8] D. Kielpinski *et al.*, Nature, 417, 709-711 (2002) [9] G. Zarantonello *et al.*, PRL 123, 260503 (2019)

Outlook

Future plans

• Characterization of the in situ Ar+ cleaning [6]

• Include dynamical decoupling schemes and perform randomized benchmarking.

• Develop next generation multilayer trap system [7,8]

